

FSL3806-VB TO262 Datasheet **Power MOSFET**

PRODUCT SUMMARY					
V _{DS} (V)	60				
R _{DS(on)} (Ω)	V _{GS} = 10 V 0.015				
Q _g (Max.) (nC)	110				
Q _{gs} (nC)	29				
Q _{gd} (nC)	36				
Configuration	Single				

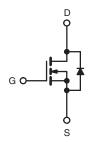
FEATURES

- · Advanced process technology
- 175 °C operating temperature
- · Fast switching









N-Channel MOSFET

ABSOLUTE MAXIMUM RATINGS (T _C = 25 °C, unless otherwise noted)						
PARAMETER			SYMBOL	LIMIT	UNIT	
Drain-Source Voltage			V_{DS}	60	V	
Gate-Source Voltage			V_{GS}	± 20	V I	
Continuous Drain Current ^f	\/ at 10 \/	$T_C = 25 ^{\circ}C$	_	60		
Continuous Drain Current	V _{GS} at 10 V	T _C = 100 °C	I _D	50	Α	
Pulsed Drain Current a, e			I _{DM}	290		
Linear Derating Factor				1.3	W/°C	
Single Pulse Avalanche Energy b, e			E _{AS}	100	mJ	
Maximum Bayyar Dissination	T _C = 25 °C		D-	190	w	
Maximum Power Dissipation	T _A = 25 °C		P_{D}	3.7		
Peak Diode Recovery dV/dt ^{c, e}			dV/dt	4.5	V/ns	
Operating Junction and Storage Temperature Range			T _J , T _{stg}	-55 to +175	°C	
Soldering Recommendations (Peak temperature) d for 10 s		•	300	7		

Notes

- a. Repetitive rating; pulse width limited by maximum junction temperature (see fig. 11). b. V_{DD} = 25 V, Starting T_J = 25 °C, L = 22 μ H, R_g = 25 Ω , I_{AS} = 72 A (see fig. 12). c. I_{SD} ≤ 72 A, I_{AS} = 72 A (see fig. 12). d. 1.6 mm from case. e. Uses IRFZ48, SiHFZ48 data and test conditions.

- f. Calculated continuous current based on maximum allowable junction temperature.



THERMAL RESISTANCE RATINGS					
PARAMETER	SYMBOL	TYP.	MAX.	UNIT	
Maximum Junction-to-Ambient (PCB mount) ^a	R _{thJA}	-	40	°C/W	
Maximum Junction-to-Case (Drain)	R_{thJC}	-	0.8		

Note

a. When mounted on 1" square PCB (FR-4 or G-10 material).

PARAMETER	SYMBOL	TEST CONDITIONS		MIN.	TYP.	MAX.	UNIT
Static						L	
Drain-Source Breakdown Voltage	V _{DS}	V _{GS}	= 0, I _D = 250 μA	60	-	-	V
V _{DS} Temperature Coefficient	$\Delta V_{DS}/T_{J}$	Reference	e to 25 °C, I _D = 1 mA °	-	0.060	-	V/°C
Gate-Source Threshold Voltage	V _{GS(th)}	V _{DS} =	· V _{GS} , I _D = 250 μA	1.5	-	3.0	V
Gate-Source Leakage	I _{GSS}	,	V _{GS} = ± 20 V	-	-	± 100	nA
Zoro Coto Voltago Drain Current		V _{DS} :	= 60 V, V _{GS} = 0 V	=	-	25	μА
Zero Gate Voltage Drain Current	I_{DSS}	V _{DS} = 48 V	, V _{GS} = 0 V, T _J = 150 °C	-	-	250	
Drain-Source On-State Resistance	R _{DS(on)}	V _{GS} = 10 V	I _D = 15 A ^b	-	0.015	-	Ω
Forward Transconductance	9 _{fs}	V _{DS} =	25 V, I _D = 15 A ^b	27	-	-	S
Dynamic							
Input Capacitance	C _{iss}		$V_{GS} = 0 V$,		3500	-	
Output Capacitance	C _{oss}		$V_{DS} = 25 \text{ V},$	-	1300	-	pF
Reverse Transfer Capacitance	C _{rss}	f = 1.0 MHz, see fig. 5 ^c		-	190	-	1
Total Gate Charge	Qg			-	-	110	nC
Gate-Source Charge	Q _{gs}	V _{GS} = 10 V	$I_D = 12 \text{ A}, V_{DS} = 48 \text{ V},$ see fig. 6 and 13 b, c	=	-	29	
Gate-Drain Charge	Q _{gd}		see lig. 6 and 13 s, s		-	36	
Turn-On Delay Time	t _{d(on)}	V _{DD} = 30 V, I _D = 12 A,		-	8.1	-	
Rise Time	t _r			-	250	-	
Turn-Off Delay Time	t _{d(off)}	$R_g = 9.1 \Omega, R$	$_{\rm D}$ = 0.34 Ω , see fig. 10 b, c	-	210	-	ns
Fall Time	t _f			-	250	-	
Internal Source Inductance	L _S	Between lead	, and center of die contact	-	7.5	-	nΗ
Drain-Source Body Diode Characteristic	s						
Continuous Source-Drain Diode Current	I _S	showing the	MOSFET symbol showing the		-	50°	_
Pulsed Diode Forward Current ^a	I _{SM}	integral reverse p - n junction diode		-	-	90	A
Body Diode Voltage	V_{SD}	$T_J = 25 ^{\circ}\text{C}, I_S = 72 \text{A}, V_{GS} = 0 \text{V}^{ \text{b}}$		-	-	2.0	V
Body Diode Reverse Recovery Time	t _{rr}	- T _J = 25 °C, I _F = 72 A, dl/dt = 100 A/µs b, c		-	120	180	ns
Body Diode Reverse Recovery Charge	Q _{rr}			-	500	800	μC
Forward Turn-On Time	t _{on}	Intrinsic turn-on time is negligible (turn-on is dominated by L_S and L_D)				L _D)	

Notes

- a. Repetitive rating; pulse width limited by maximum junction temperature (see fig. 11). b. Pulse width $\leq 300~\mu s$; duty cycle $\leq 2~\%.$ c. Uses VBL1615/FSL3806-VB TO262 data and test conditions.

- d. Calculated continuous current based on maximum allowable junction temperature.



TYPICAL CHARACTERISTICS (25 °C, unless otherwise noted)

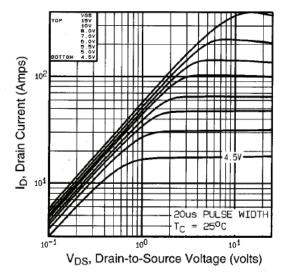


Fig. 1 - Typical Output Characteristics

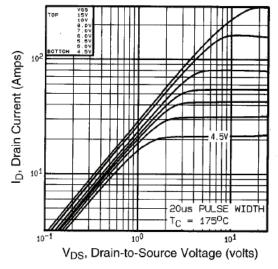


Fig. 2 - Typical Output Characteristics

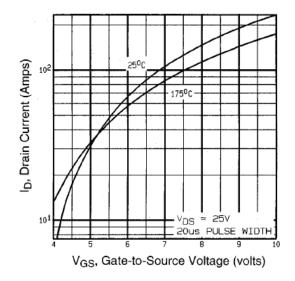


Fig. 3 - Typical Transfer Characteristics

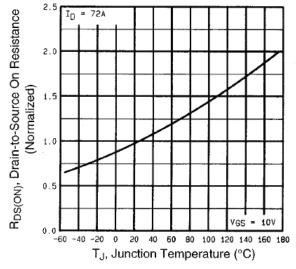


Fig. 4 - Normalized On-Resistance vs. Temperature



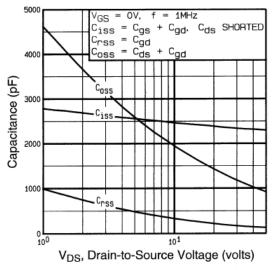


Fig. 5 - Typical Capacitance vs. Drain-to-Source Voltage

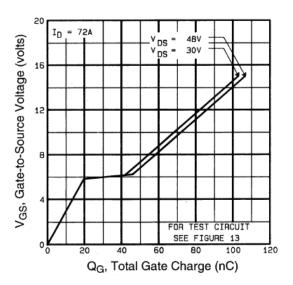


Fig. 6 - Typical Gate Charge vs. Gate-to-Source Voltage

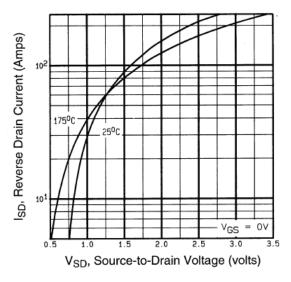


Fig. 7 - Typical Source-Drain Diode Forward Voltage

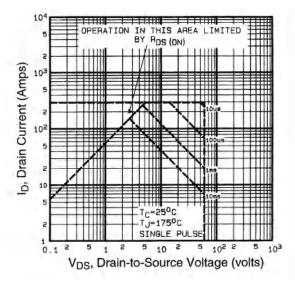


Fig. 8 - Maximum Safe Operating Area



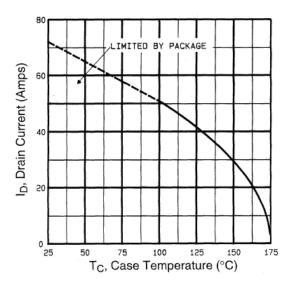


Fig. 9 - Maximum Drain Current vs. Case Temperature

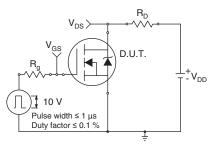


Fig. 10a - Switching Time Test Circuit

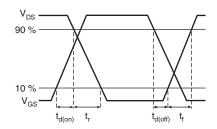
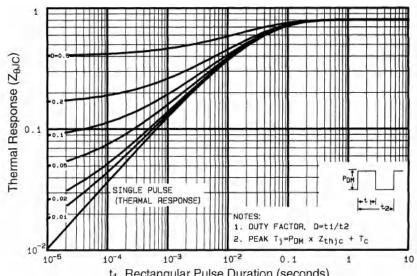


Fig. 10b - Switching Time Waveform



 $t_1,\,Rectangular\,Pulse\,Duration\,(seconds)\\ \mbox{Fig. 11 - Maximum Effective Transient Thermal Impedance, Junction-to-Case}$

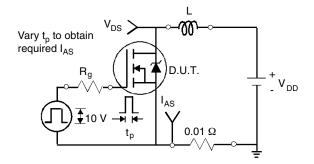


Fig. 12a - Unclamped Inductive Test Circuit

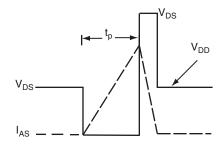


Fig. 12b - Unclamped Inductive Waveforms



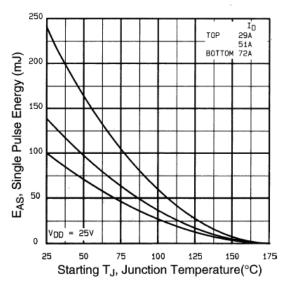


Fig. 12c - Maximum Avalanche Energy vs. Drain Current

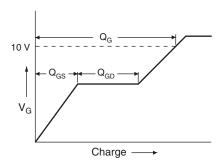


Fig. 13a - Maximum Avalanche Energy vs. Drain Current

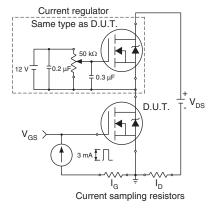
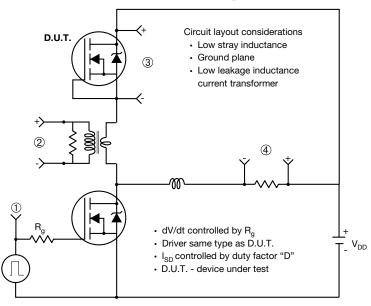


Fig. 13b - Gate Charge Test Circuit



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Peak Diode Recovery dV/dt Test Circuit



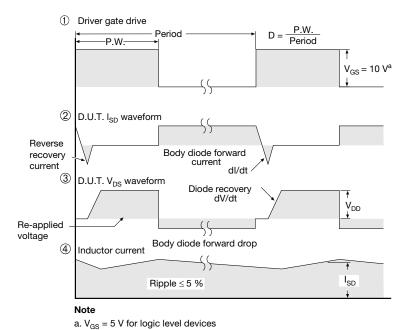
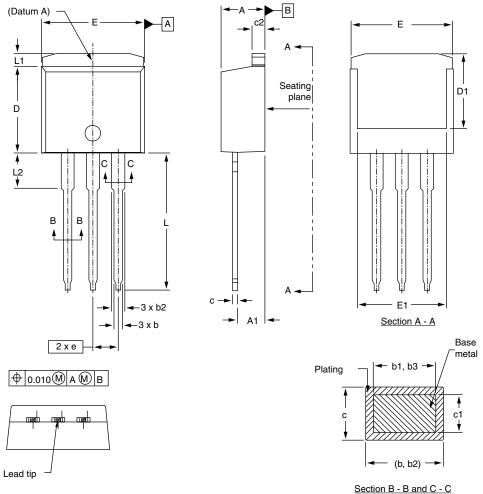


Fig. 14 - For N-Channel



I²PAK (TO-262) (HIGH VOLTAGE)



	MILLIMETERS		INC	HES
DIM.	MIN.	MAX.	MIN.	MAX.
Α	4.06	4.83	0.160	0.190
A1	2.03	3.02	0.080	0.119
b	0.51	0.99	0.020	0.039
b1	0.51	0.89	0.020	0.035
b2	1.14	1.78	0.045	0.070
b3	1.14	1.73	0.045	0.068
С	0.38	0.74	0.015	0.029
c1	0.38	0.58	0.015	0.023
c2	1.14	1.65	0.045	0.065

	MILLIMETERS		INC	HES
DIM.	MIN.	MAX.	MIN.	MAX.
D	8.38	9.65	0.330	0.380
D1	6.86	-	0.270	-
Е	9.65	10.67	0.380	0.420
E1	6.22	-	0.245	-
е	2.54	BSC	0.100	BSC
L	13.46	14.10	0.530	0.555
L1	-	1.65	-	0.065
L2	3.56	3.71	0.140	0.146

Scale: None

ECN: S-82442-Rev. A, 27-Oct-08

DWG: 5977

Notes

- 1. Dimensioning and tolerancing per ASME Y14.5M-1994.
- 2. Dimension D and E do not include mold flash. Mold flash shall not exceed 0.127 mm per side. These dimensions are measured at the outmost extremes of the plastic body.
- 3. Thermal pad contour optional within dimension E, L1, D1, and E1.
- 4. Dimension b1 and c1 apply to base metal only.



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